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Pressure Dependence of Creep in Zn and Cd*

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Bending creep in Zn is reported as a function of hydrostatic confining pressure P up to 8 kbars. The ratio of activation volume for creep to atomic volume, $\Delta V^{\ddagger}/V_0 = 0.65 - 0.044 \ P$ (P in kbars), is essentially independent of temperature between 27° and 57°C. The ratio $\Delta V^{\ddagger}/V_0 = 0.63 - 0.035 \ P$ for creep of Cd is independent of temperature between 0° to 57°C. $\Delta V^{\ddagger}/V_0$ for Zn at a given pressure was 5 to 15% higher for creep than for self-diffusion in the basal plane reported by Liu and Drickamer.

INTRODUCTION

THE ratio of activation volume for creep to roompressure atomic volume, $\Delta V^{\ddagger}/V_0$, in an alkali halide¹ (AgBr), fcc^{2,3} Pb, bcc Na,⁴ and tetragonal⁵ Sn have been reported independent of hydrostatic confining pressure. Where diffusion data were available for comparison, the activation volume ratios for creep and diffusion were similar. This paper reports similar studies on hcp Zn and Cd. The pressure dependence of the ratio $\Delta V^{\ddagger}/V_0$ in Zn, as reported by Liu and Drickamer,⁶ is shown in Fig. 1 by triangles for self-diffusion along the c axis, and by squares along the basal plane.

SAMPLE PREPARATION AND EXPERIMENTAL PROCEDURE

Samples were prepared from 99.999% Zn and Cd purchased from the American Smelting and Refining Company. The Zn, received as spatters, was melted and

cast in vacuum into an ingot approximately $\frac{3}{8}$ in. in diameter and several inches long. The Cd was received as $\frac{3}{8}$ -in.-diam rods. In each case an ingot of material was compressed in a press to approximately 0.2-cm thickness, then cut and filed to size: $0.177 \times 0.177 \times 2.5$ cm for Zn and $0.2 \times 0.2 \times 2.5$ cm for Cd. The specimens were then annealed in a vacuum for one hour at 300°C (for Zn) or 100°C (for Cd). The final average grain size was 0.3 mm (Zn) or 0.1 mm (Cd).

The pressure equipment, three-point loading device, and deflection measuring apparatus have been described. 3.5 The sensitivity of the differential transformer circuit was 5 V/cm. Deflection rates between about 2×10^{-8} and 10^{-5} cm/sec were observed. The spring-applied load, about 1 kg, corresponded to a maximum tensile stress of 55 kg/cm² and 35 kg/cm² for typical Zn and Cd samples, respectively; varied 50% from sample to sample (depending on individual sample size); and changed during any run by approximately 10% because the sample deformation resulted in a change of spring elongation.

RESULTS AND DISCUSSION

Figure 2 shows a typical creep series for Zn and for Cd where the pressure P has been alternately increased and decreased at intervals of approximately one hour. In the determination of the activation volume, the slope within each of these intervals was determined. Each

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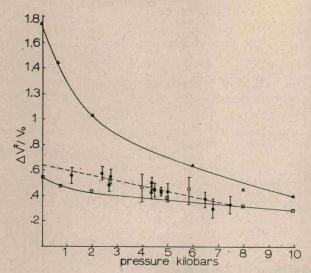


Fig. 1. Activation volume ratio for Zn. Results of the present creep study are given by open circles for 57° C, and dark circles for 27° C. Results of Liu and Drickamer are given by triangles for self-diffusion along c axis, and squares in the basal plane.

rate was then used, along with the geometric mean of the rates of the interval preceding and following it, in the determination of the ratio,

$$\Delta V^{\ddagger}/V_0 = [kT/V_0(P_2 - P_1)] \ln(\epsilon_1/\dot{\epsilon}_2), \qquad (1)$$

where V_0 is the room-temperature room-pressure atomic volume, k is Boltzmann's constant, T the absolute temperature, and $\dot{\epsilon}_1$ the deformation rate at pressure P_1 .

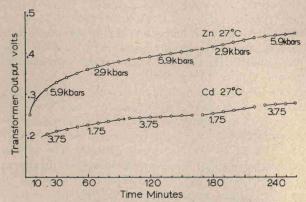


Fig. 2. Typical segments of creep curves for Zn and Cd for which pressure has been varied at periodic intervals.

The activation volume to atomic volume ratio shown in Fig. 1 is a function of the average of the pressures used in Eq. (1). The error bars of Fig. 1 are the extremes in the volume ratio at a given pressure on a given sample. The dashed straight line was determined by least squares fitting. The present data are not inconsistent with a curvilinear dependence of $\Delta V^{\dagger}/V_0$ upon P, but such a construction would be somewhat arbitrary.

Liu and Drickamer⁶ report the coefficient of self-diffusion parallel to the c axis is greater than that for self-diffusion perpendicular to the c axis. They found the self-diffusion rate in polycrystals to be intermediate between those of single crystals in directions parallel and perpendicular to the c axis. The activation volume ratio for creep lies slightly above that for diffusion in the

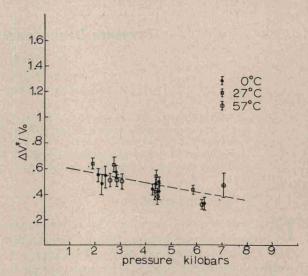


Fig. 3. Activation volume ratio for creep in Cd.

basal plane. The present creep studies were carried out at 27° and 57°C, the diffusion studies were carried out at 307°C. If the activation volume ratio is not strongly temperature-dependent, these studies lend support to a mechanism in which creep is controlled by self-diffusion in the basal plane.

Figure 3 shows the activation volume ratio $\Delta V^{\ddagger}/V_0$ versus pressure for creep in Cd. There are no diffusion data for comparison, but the effect appears to be similar to that in Zn, that is $\Delta V^{\ddagger}/V_0$ is about the same for both metals at a given pressure.